



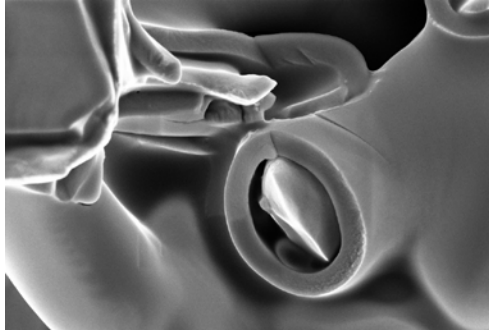
Polymer Tantalum Capacitors for Advanced High Reliability Applications

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Tantalum Capacitors – Dielectric Contacting

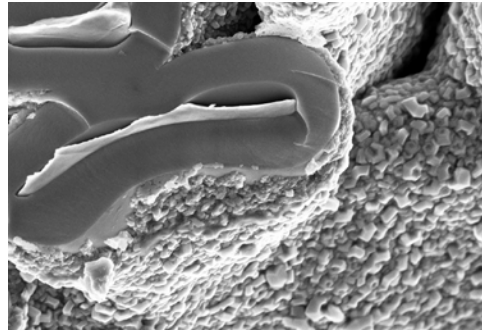
Liquid electrolyte



WET Tantalums

- ionic conduction
- hermetically sealed
- + surge robust
- + high voltage
- + high temperature
- temperature dependent
- frequency dependent
- electrolyte leak possible

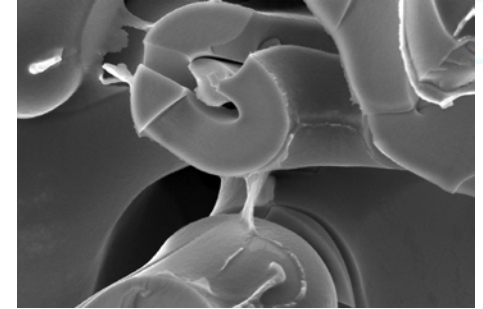
MnO₂



Solid - MnO₂

- electronic conduction
- + high temperature
- + well established reliability
- failure mode
- voltage limited
- ESR higher

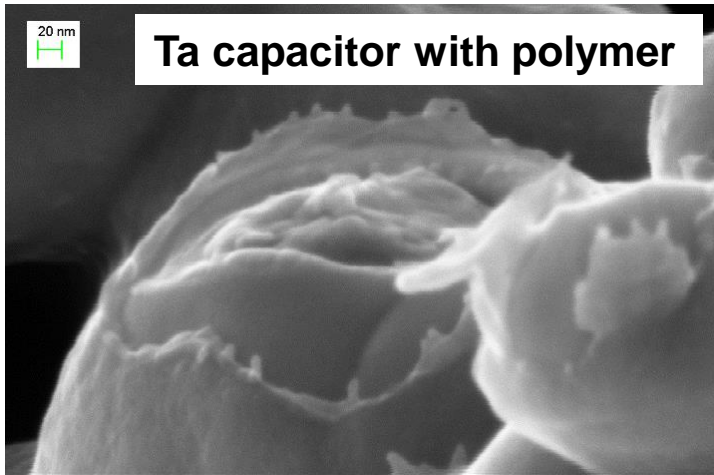
Polymer



Solid - Polymer

- electronic conduction
- + low ESR
- + safe failure mode
- + high voltage
- temperature limited
- humidity & oxygen sensitive

Hermetically Sealed Polymer Capacitor



Why Hermetical Packaging

Thin cathode layers under extreme condition are subject of potential degradation

Stable low ESR

Stable parts under extreme conditions

Solution developed with ESA partnership



TCH Series Hermetic seal:

Protects from degradation by humidity

Protects from degradation by oxidation



High Voltage Low ESR Polymer Capacitor

Basic concept

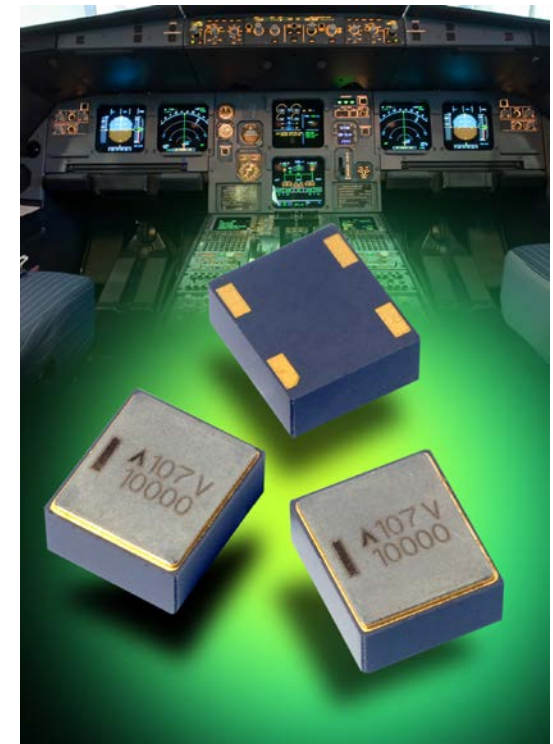
- optimized anode with robust dielectric
- pre-polymerized PEDT based cathode material



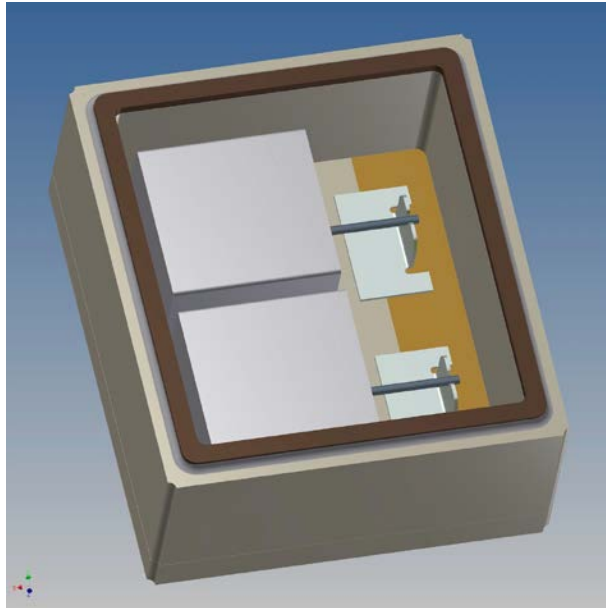
high voltage potential
up to 100 – 125V

low ESR potential

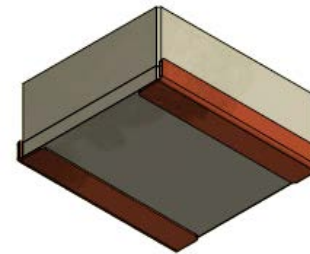
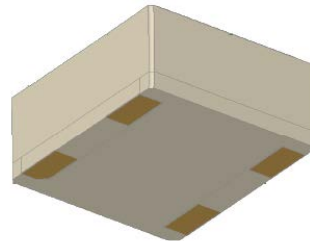
- use of special ageing and screening processes
- hermetic seal, inert atmosphere
- parallel connection of multiple capacitors



Robust Mechanical Design



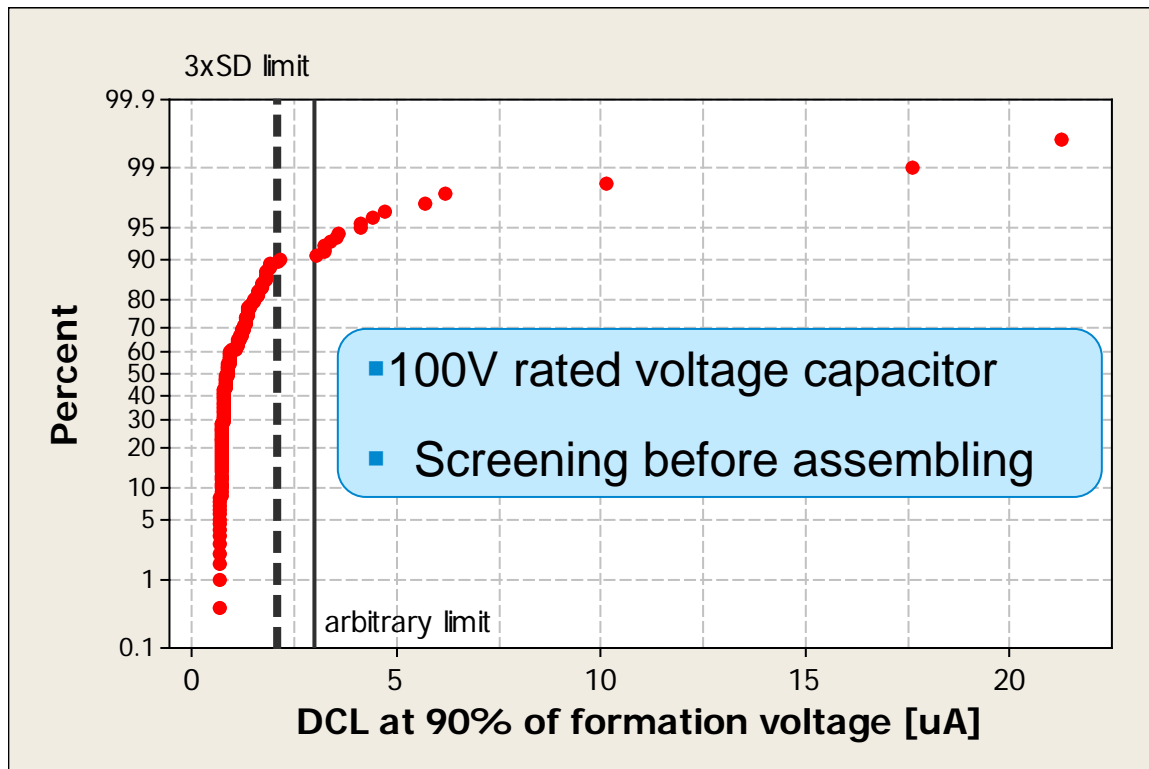
- ceramic case
- anode wire **welded** to leadframe
- leadframe **welded** to internal contacts
- internal filler applied
- inert dry atmosphere
- metal lid welded
- undertab or L-shape J lead



Mechanical Test	Method Reference	Result
Shock	100g (MIL-STD-202, Method 213, Condition C)	PASS
Vibration	20g (MIL-STD-202, Method 204, Condition D)	PASS
PIND	20g (MIL-STD-883, Method 2020, Condition A)	PASS

Ageing and Screening Procedures

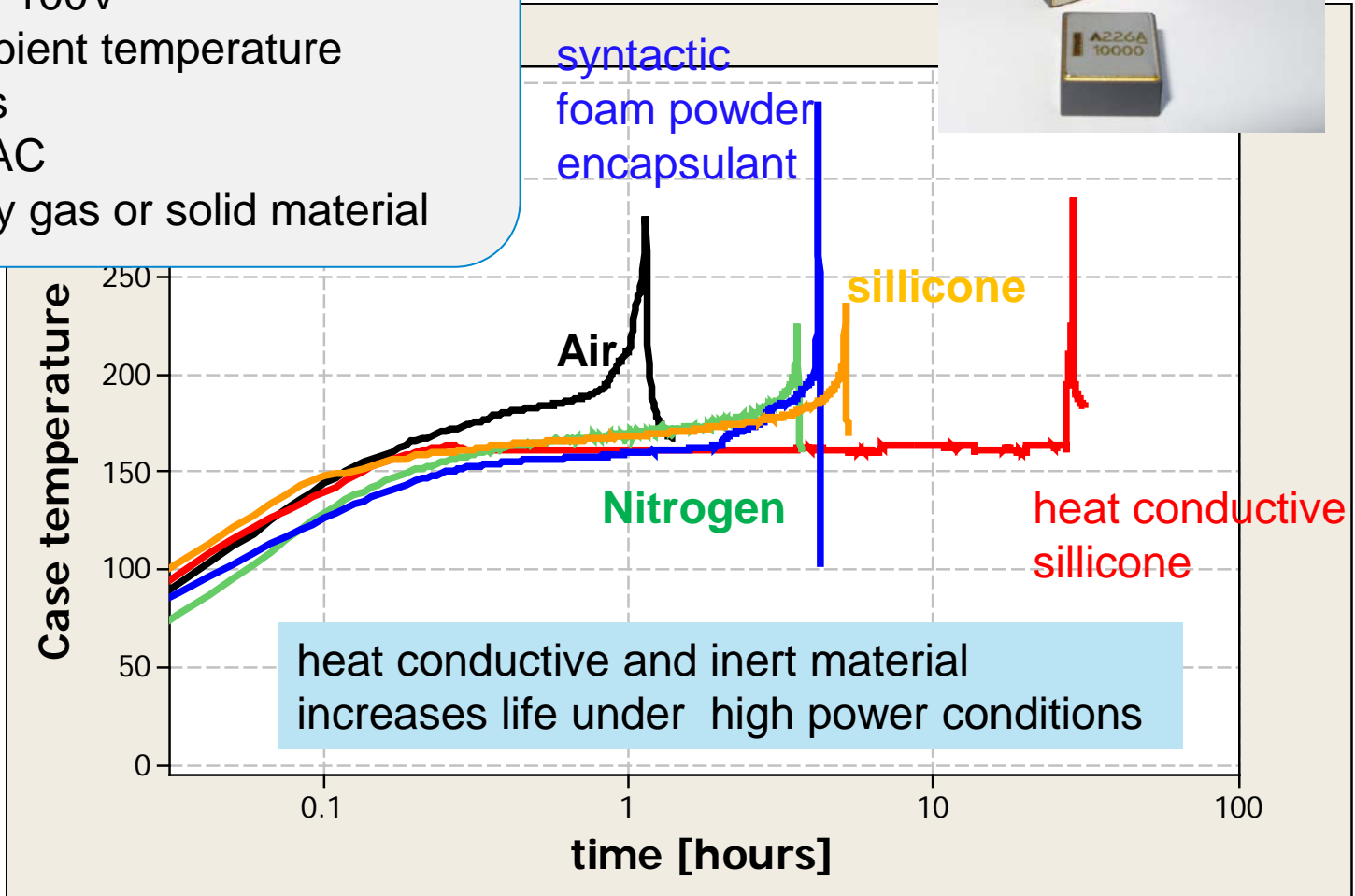
- Every capacitor is stressed by voltage
- Statistical approach applied to removal of weaker parts
- Final capacitors are aged 168h



Internal Filler Influence on Highly Accelerated Ripple Current Life

Measurement conditions:

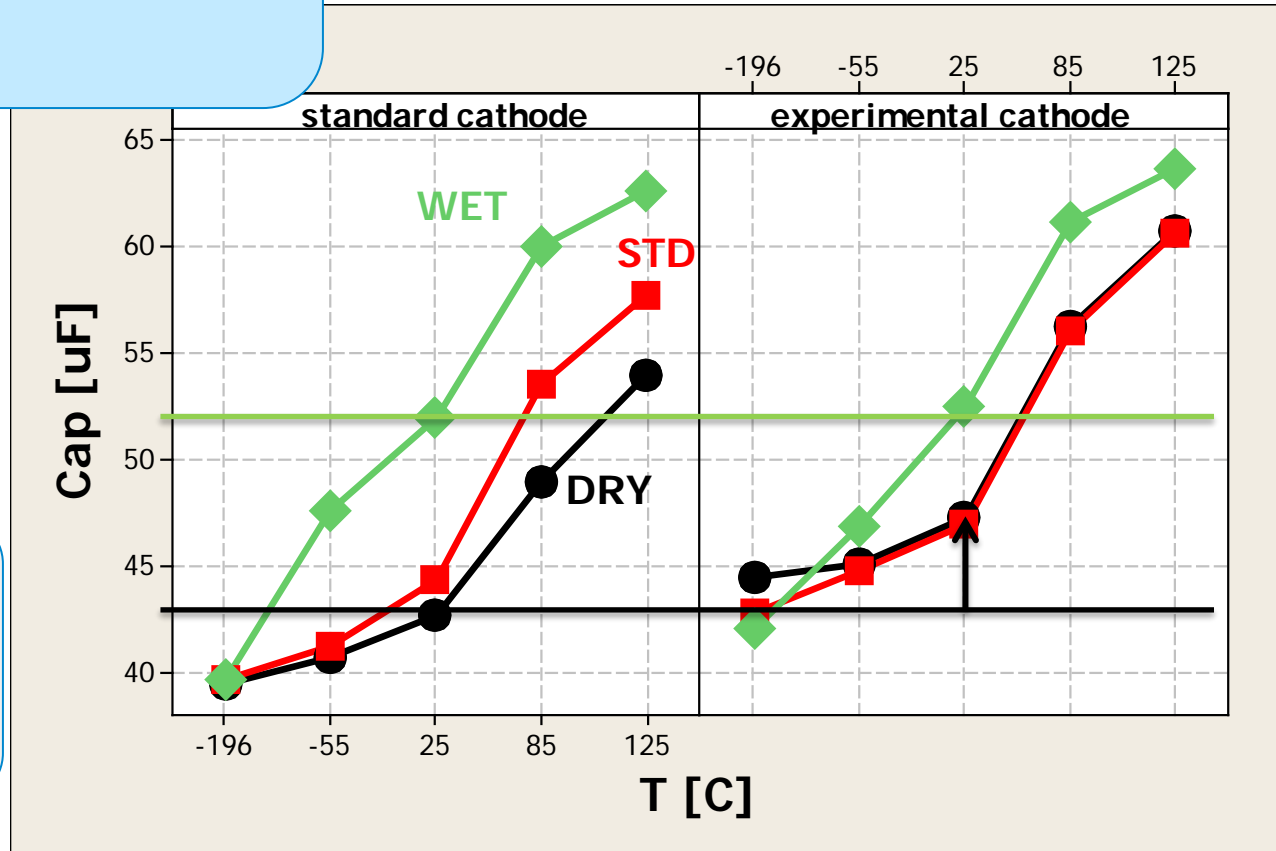
- TCH 9 22 μ F 100V
- external ambient temperature
- 10V DC bias
- 20 kHz, 8A AC
- case filled by gas or solid material



Moisture Influence on Capacitance

- capacitance retained up to $-196\text{ }^{\circ}\text{C}$
- humidity increases cap
- cathode modification can increase dry capacitance

nominal capacitance $47\mu\text{F}$



parts before final sealing:

humidified

WET

not conditioned

STD

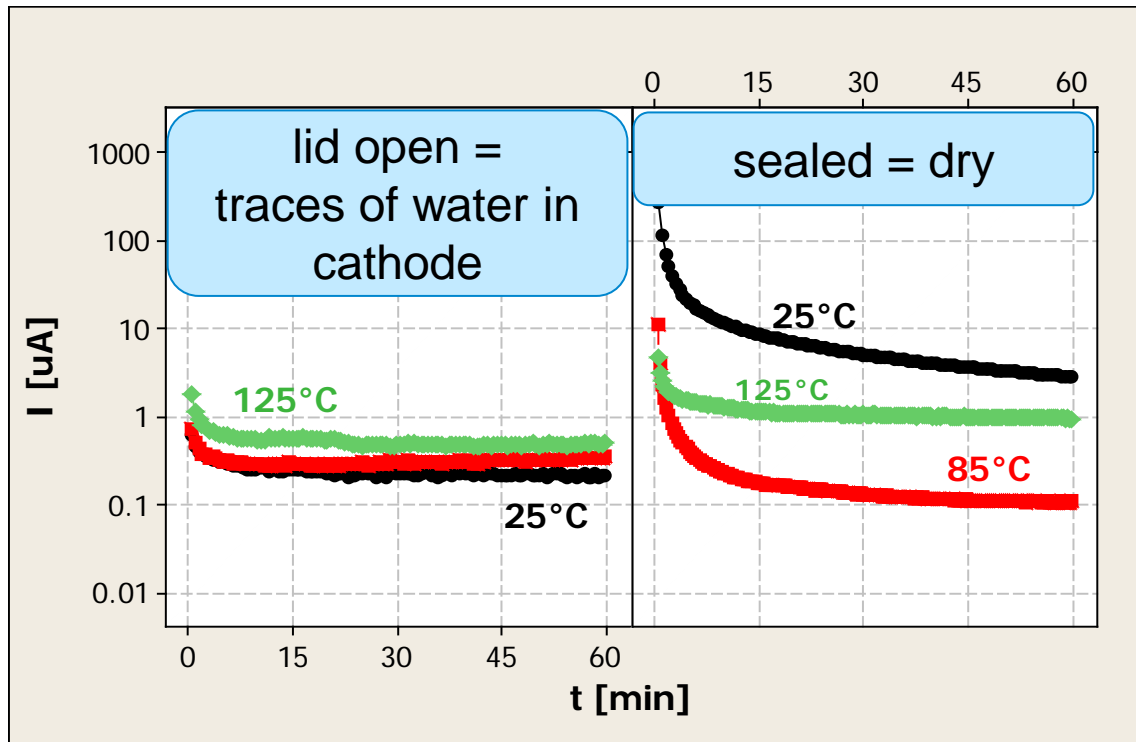
dried

DRY

Moisture Influence on DCL

fast DCL stabilization for open case or closed case and elevated temperatures

DCL measurement at temperatures
(22 μ F/ 100V)



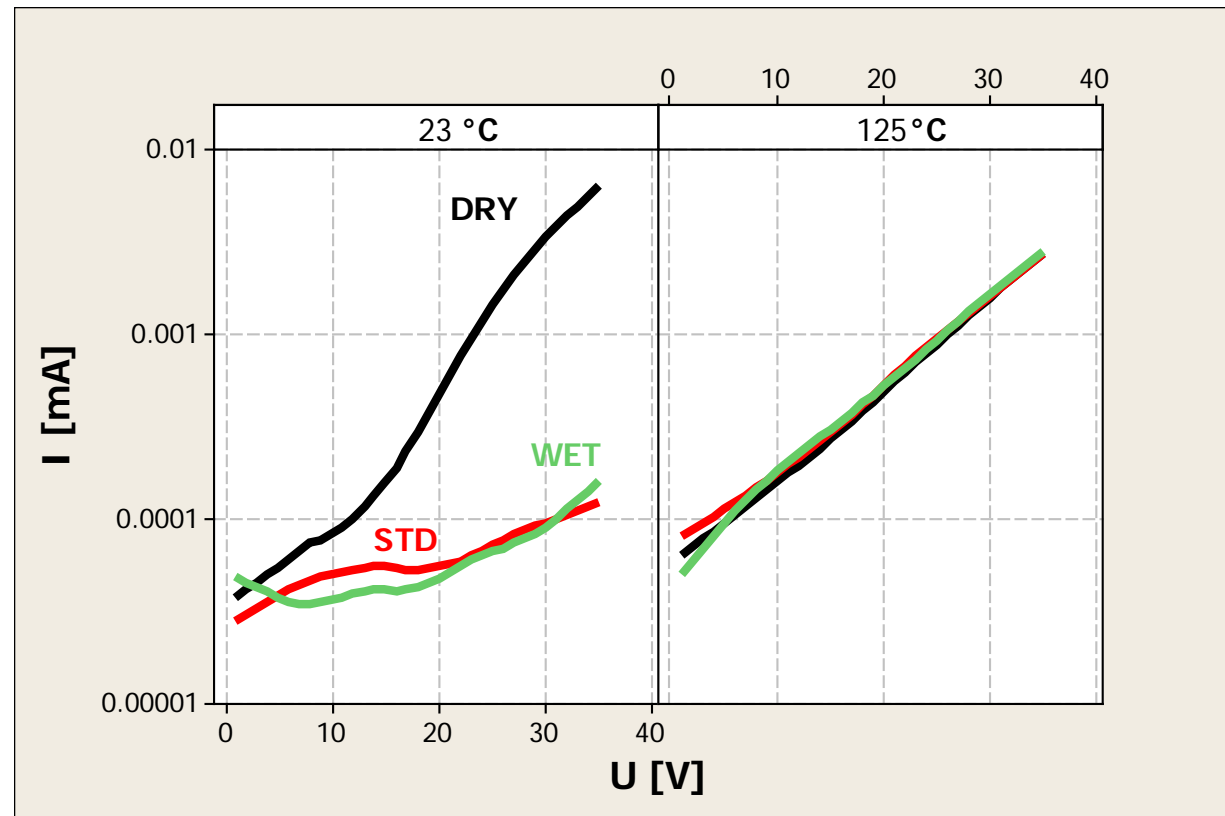
Moisture Influence on DCL

dry unit at low temperature has steeper characteristics
how is this DCL related to its stability under accelerated conditions?

V/I measurement by 1V/80s

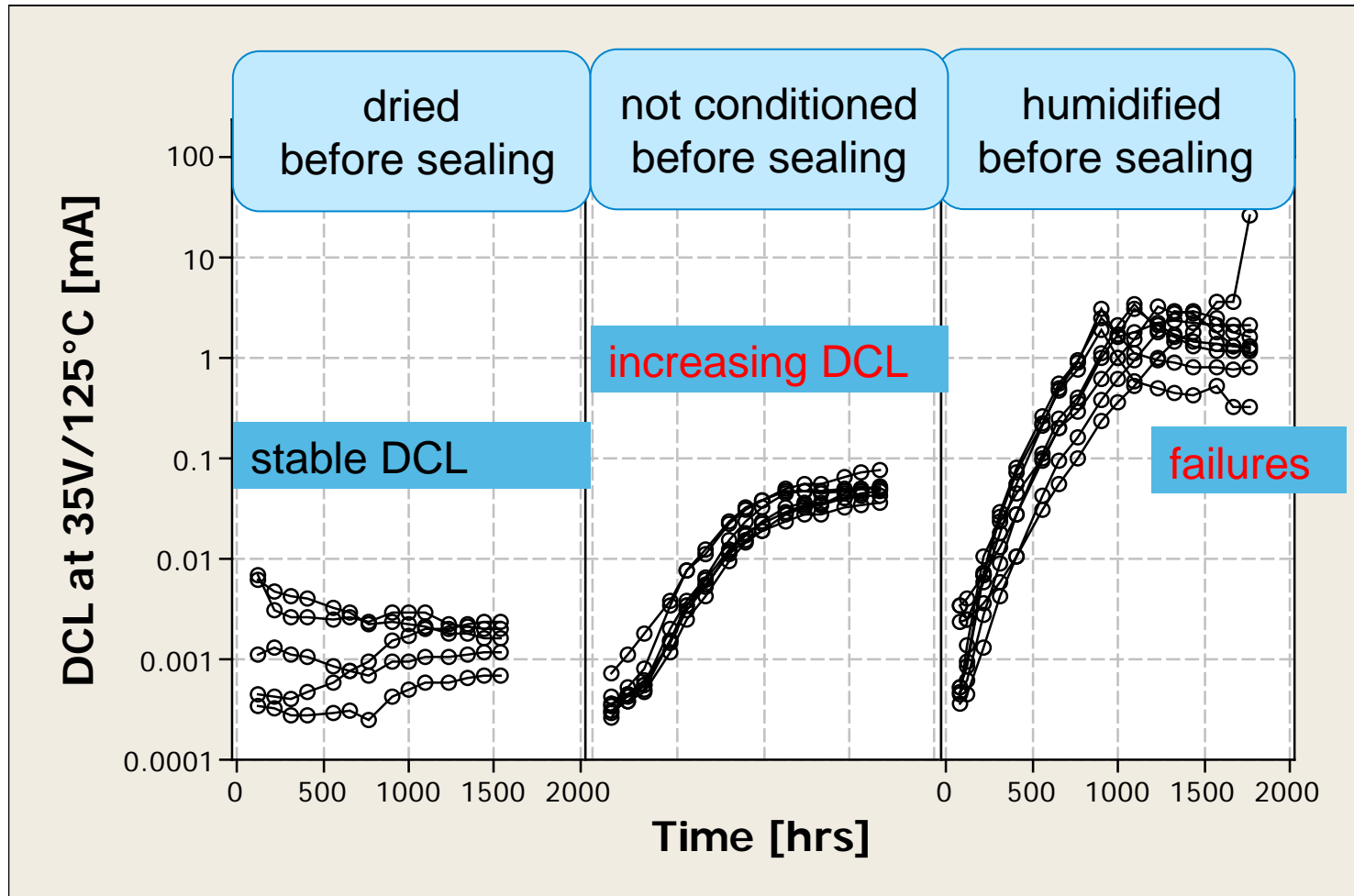
parts before final sealing:

humidified	WET
not conditioned	STD
dried	DRY

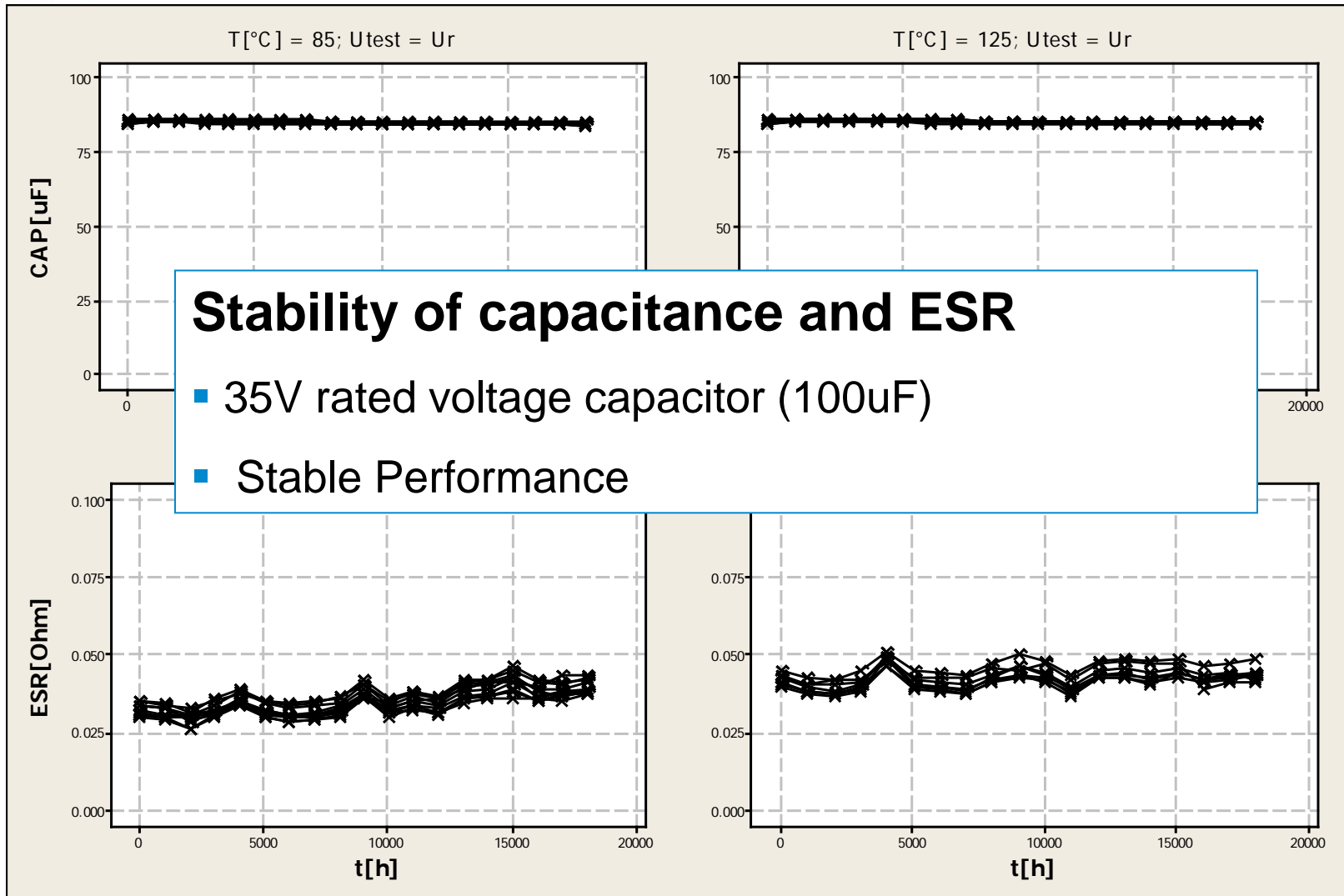


Moisture Influence on DCL Stability

Highly accelerated life test (2.1x recommended voltage/ 125°C)



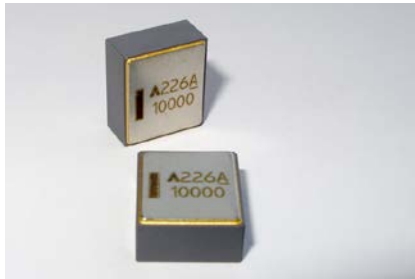
Stability of Hermetically Sealed Capacitors



Challenges – super low ESR - Modular Solution

- **TCH 9 case**

- 22 μ F/ 100V
- ESR 60 mOhm



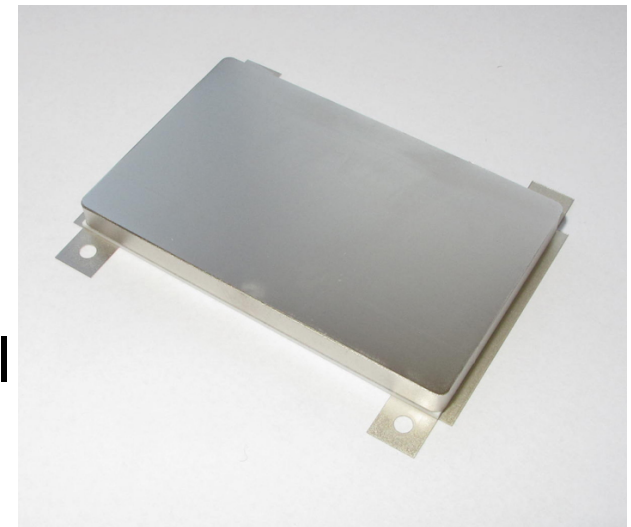
- **TO3 case**

- 100 μ F/ 100V
- ESR 9 mOhm



- **Customized case**

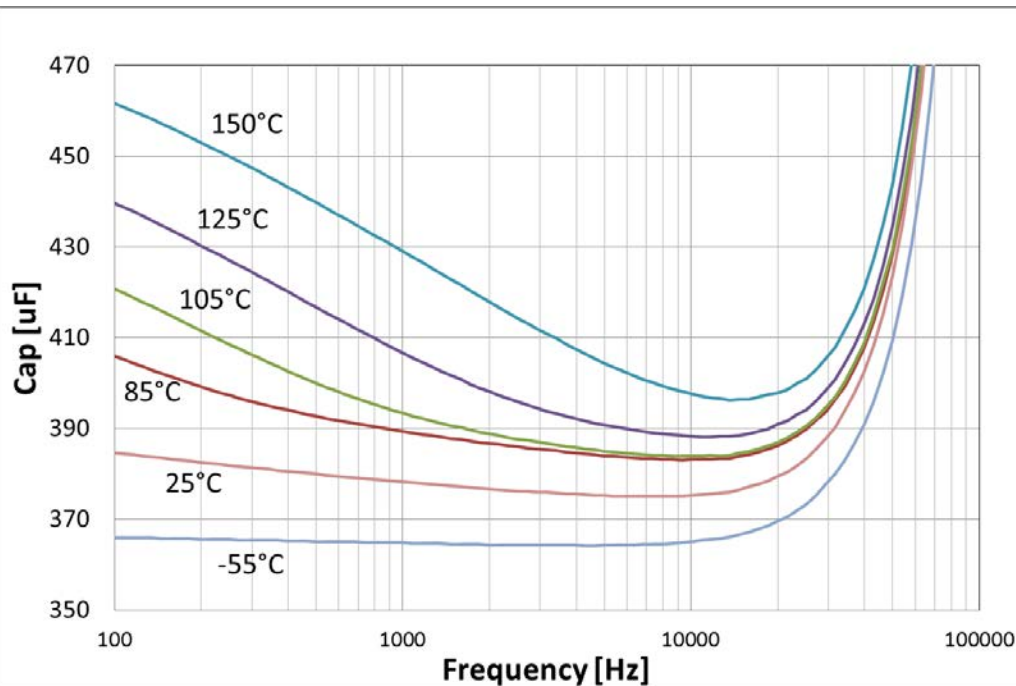
- 400 μ F/ 100V
- ESR 3 mOhm



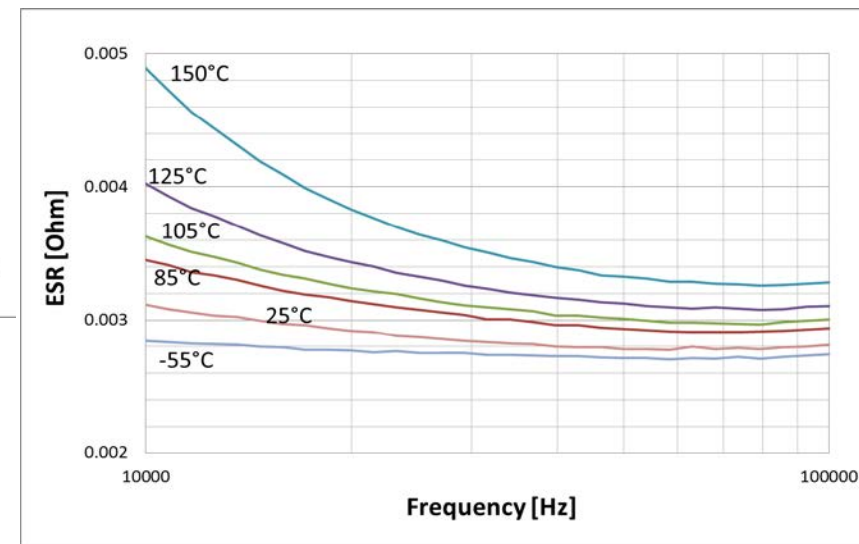
- Multiple capacitors connected in parallel
- Capacitance high
- ESR low

Challenges – super low ESR - Modular Solution

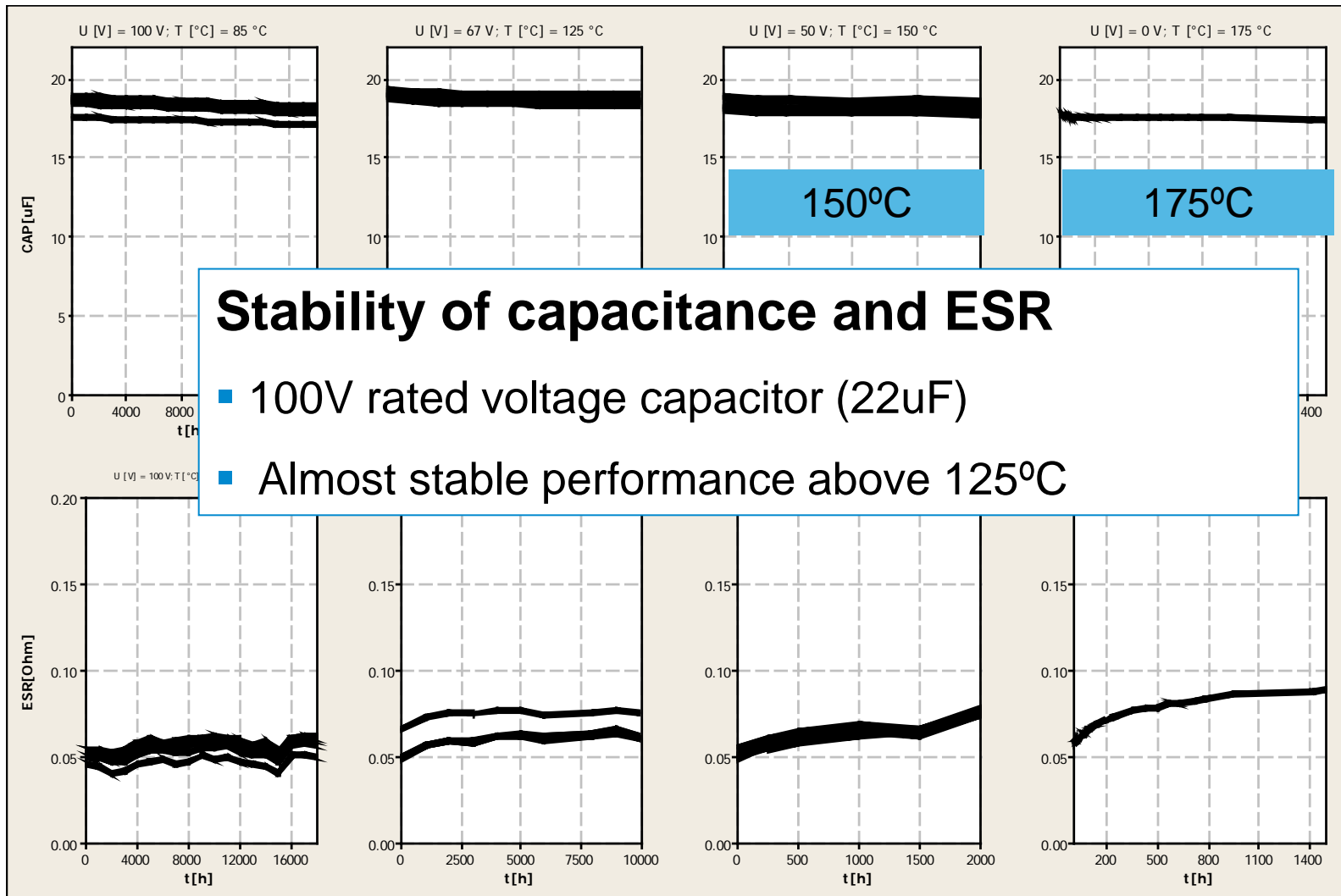
■ 400 μ F/ 100V



- Capacitance stable with temperature and frequency



Challenges – Higher Temperature

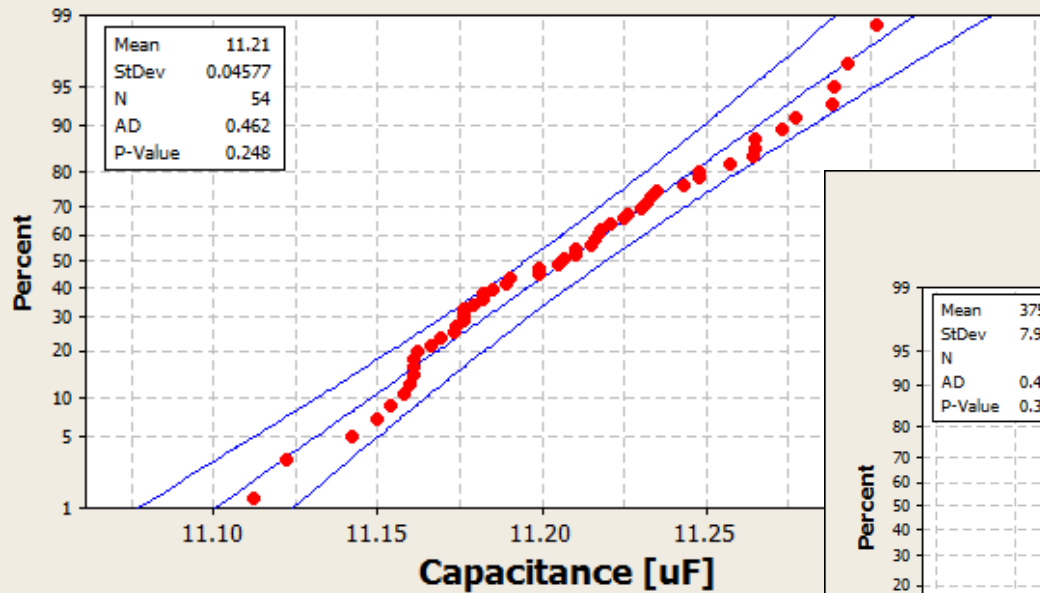


Challenges – Higher Voltage

Extremely High Voltage Ta Polymer Capacitors **TCH 9 10uF/175V**

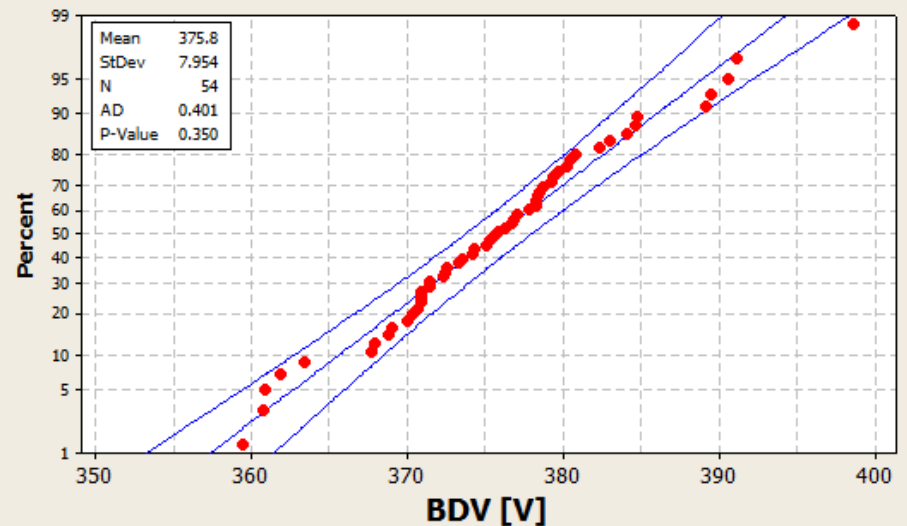
Probability Plot of 2xCap

Normal - 95% CI



Probability Plot of BDV

Normal - 95% CI



Summary & Conclusion

Hermetically Sealed Low ESR high voltage high Reliability Tantalum Capacitors

- stable performance and reliability exceeding 10,000 hours, 85°C at V_r , 125°C at $0.66xV_r$
- up to 100V rated voltages (22uF in CTC21D size)
- lightweight solution typically 2.2g per CTC21D size
- ESCC evaluation under progress

Potential for

- higher temperatures: 150°C at $0.5xV_r$ released soon
- very low ESR, high voltage, high ripple current modular solution
- higher voltages up to 175V